2SD1275, 2SD1275A

Silicon NPN triple diffusion planar type darlington

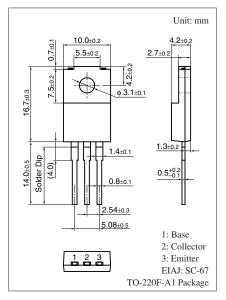
For power amplification
Complementary to 2SB0949 and 2SB0949A

Features

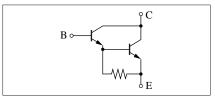
- High forward current transfer ratio h_{FE}
- High-speed switching
- Full-pack package which can be installed to the heat sink with one screw

■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage	2SD1275	V _{CBO}	60	V
(Emitter open)	2SD1275A		80	
Collector-emitter voltage	2SD1275	V _{CEO}	60	V
(Base open)	2SD1275A		80	
Emitter-base voltage (Coll	V_{EBO}	5	V	
Collector current	I_{C}	2	A	
Peak collector current	I_{CP}	4	A	
Collector power	$T_C = 25^{\circ}C$	P _C	35	W
dissipation		2.0		
Junction temperature	T _j	150	°C	
Storage temperature	T_{stg}	-55 to +150	°C	



Internal Connection



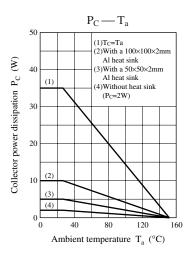
■ Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

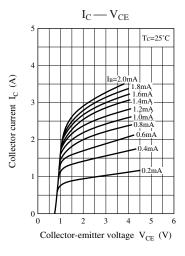
Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage	2SD1275	V_{CEO}	$I_C = 30 \text{ mA}, I_B = 0$	60			V
(Base open)	2SD1275A			80			
Base-emitter voltage		V_{BE}	$V_{CE} = 4 \text{ V}, I_{C} = 2 \text{ A}$			2.8	V
Collector-base cutoff	2SD1275	I_{CBO}	$V_{CB} = 60 \text{ V}, I_{E} = 0$			1	mA
current (Emitter open)	2SD1275A		$V_{CB} = 80 \text{ V}, I_{E} = 0$			1	
Collector-emitter cutoff	2SD1275	I_{CEO}	$V_{CE} = 30 \text{ V}, I_{B} = 0$			2	mA
current (Base open)	2SD1275A		$V_{CE} = 40 \text{ V}, I_{B} = 0$			2	
Emitter-base cutoff current (Collector open)		I_{EBO}	$V_{EB} = 5 \text{ V}, I_{C} = 0$			2	mA
Forward current transfer ratio		h _{FE1}	$V_{CE} = 4 \text{ V}, I_{C} = 1 \text{ A}$	1 000			_
		h _{FE2} *	$V_{CE} = 4 \text{ V}, I_{C} = 2 \text{ A}$	1 000		10 000	
Collector-emitter saturation	voltage	V _{CE(sat)}	$I_C = 2 \text{ A}, I_B = 8 \text{ mA}$			2.5	V
Transition frequency		f_T	$V_{CE} = 10 \text{ V}, I_{C} = 0.5 \text{ A}, f = 1 \text{ MHz}$		20		MHz
Turn-on time		t _{on}	$I_C = 2 \text{ A}, I_{B1} = 8 \text{ mA}, I_{B2} = -8 \text{ mA},$		0.5		μs
Storage time		t _{stg}	$V_{CC} = 50 \text{ V}$		4.0		μs
Fall time		t _f			1.0		μs

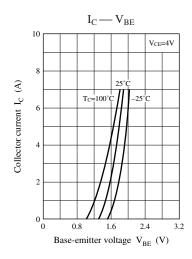
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

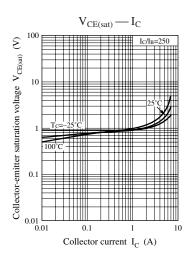
2. *: Rank classification

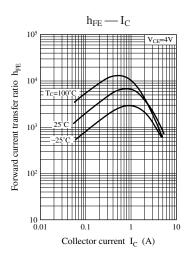
Rank	R	Q	Р	
h _{FE2}	1000 to 2500	2000 to 5000	4000 to 10000	

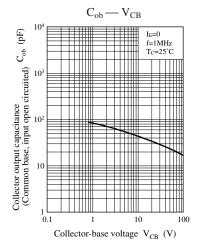


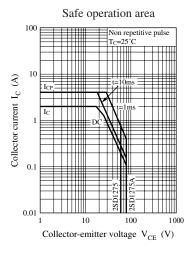


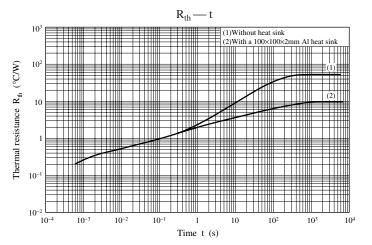












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